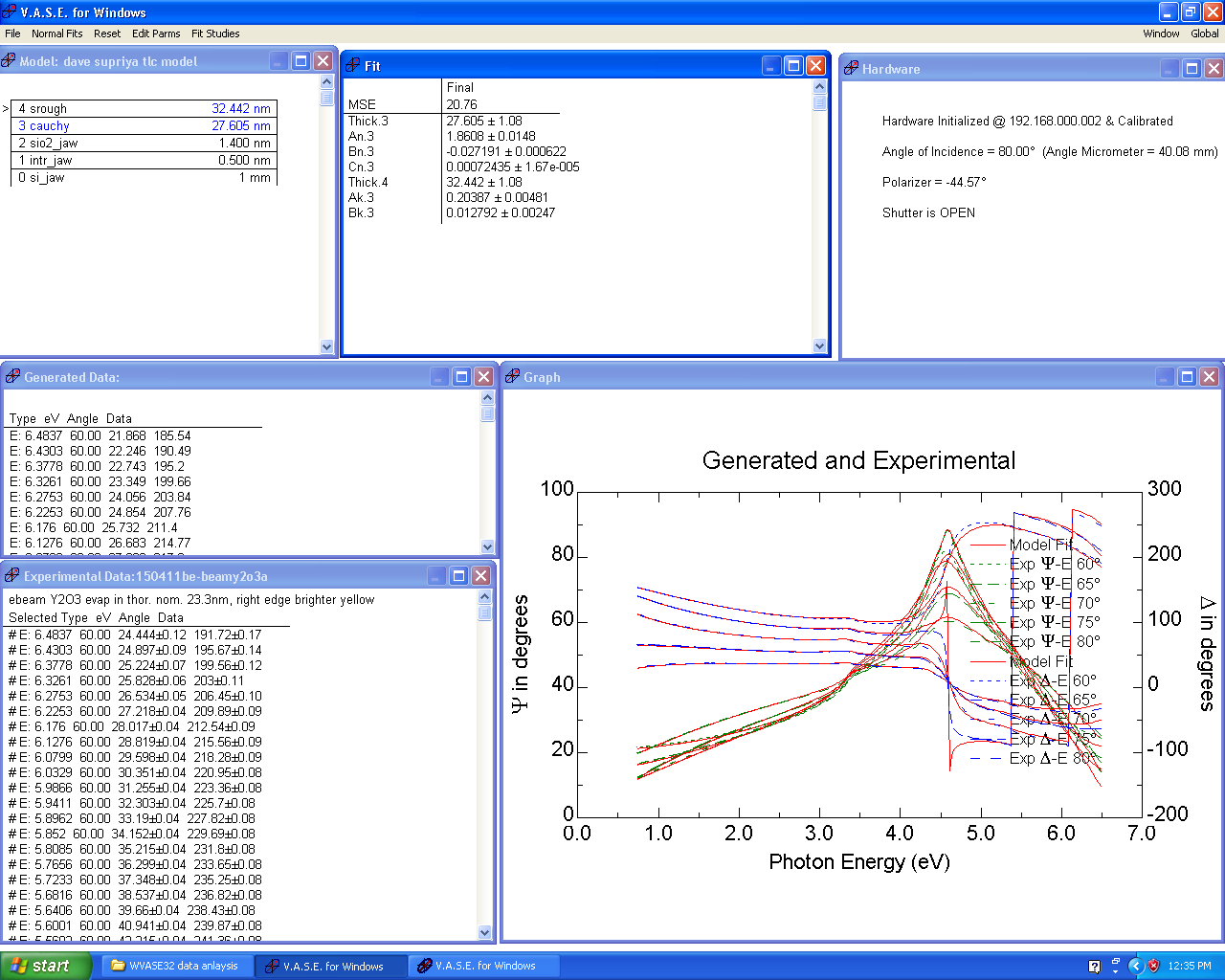
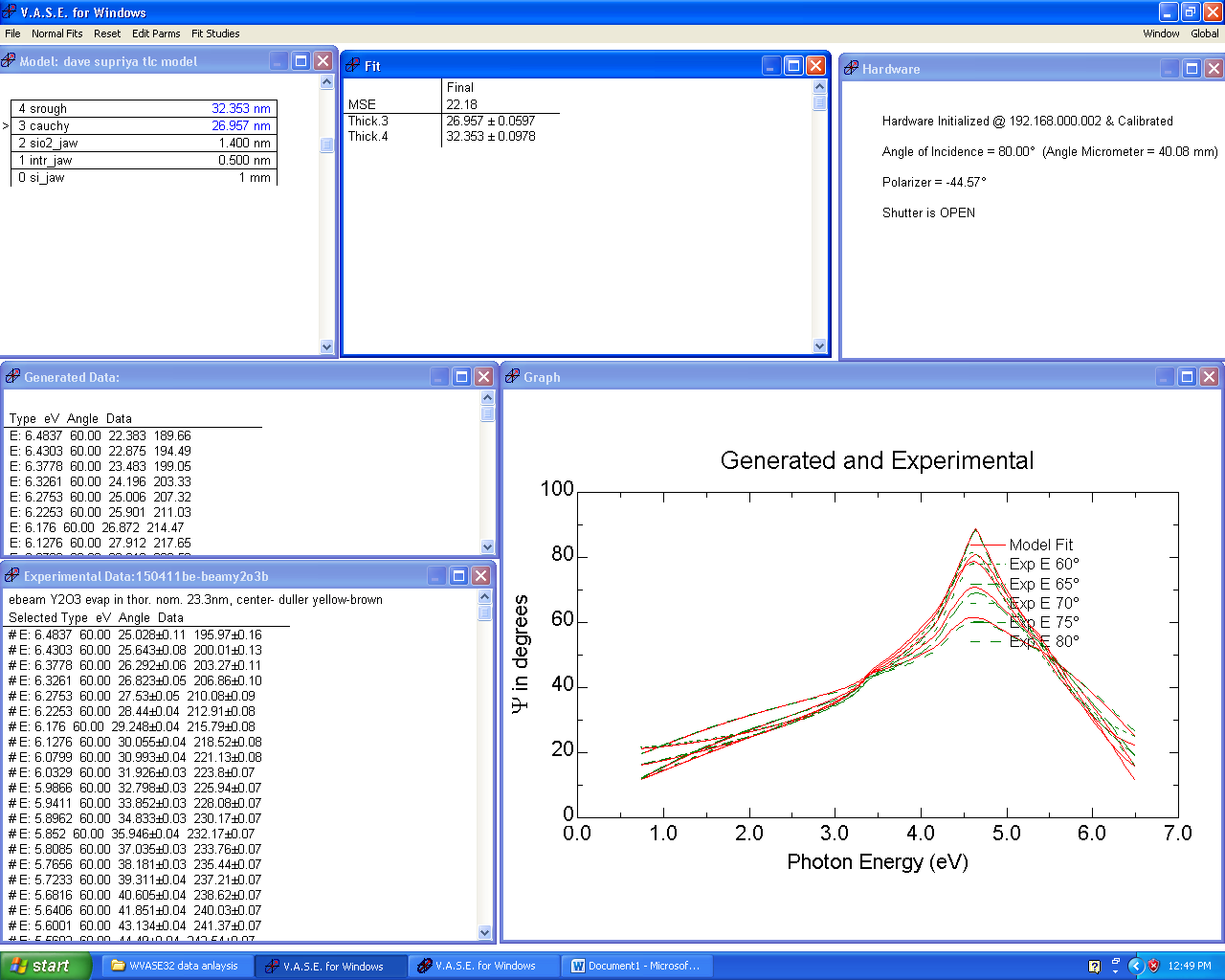
150414 measurements of 150411a&B

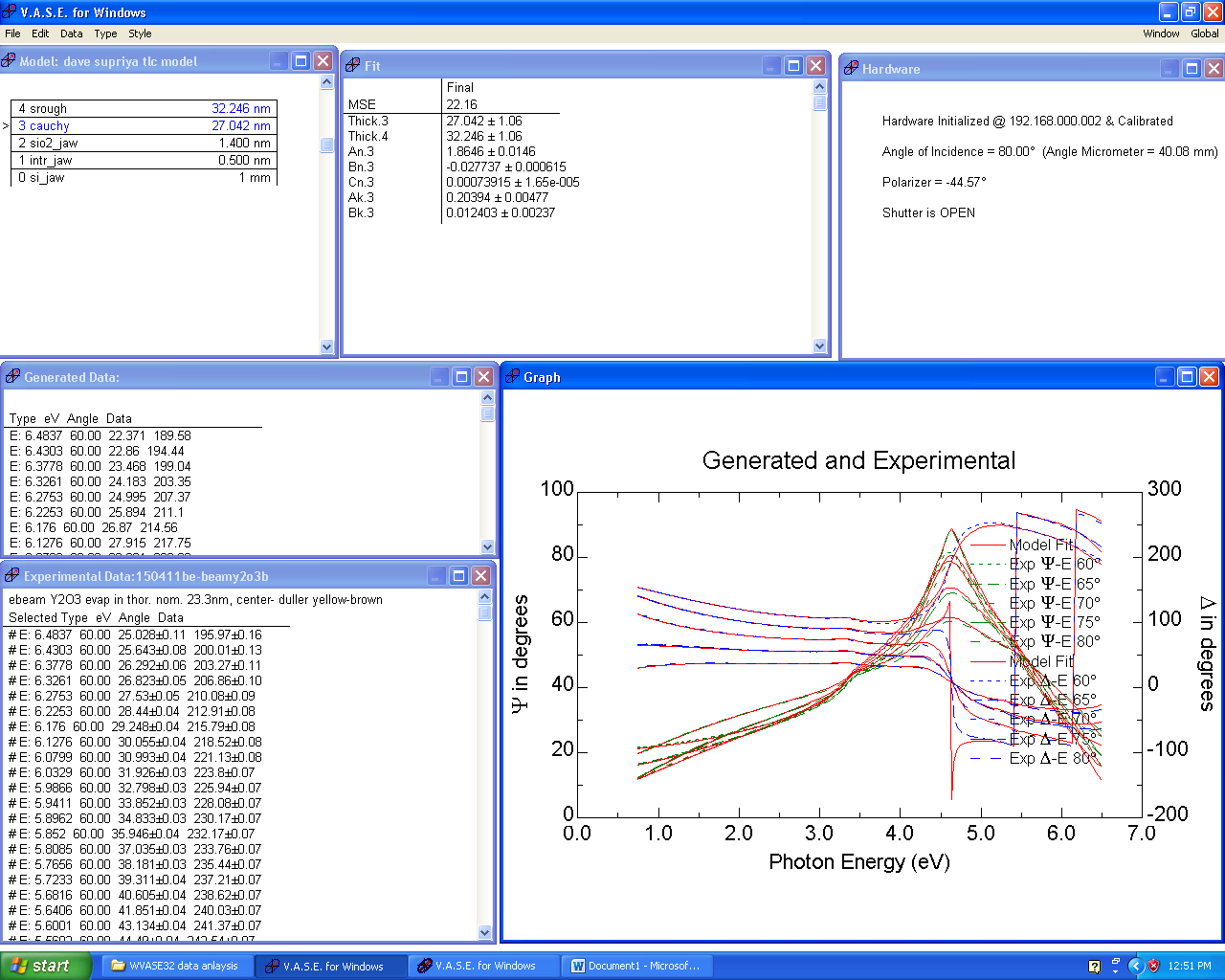
b.

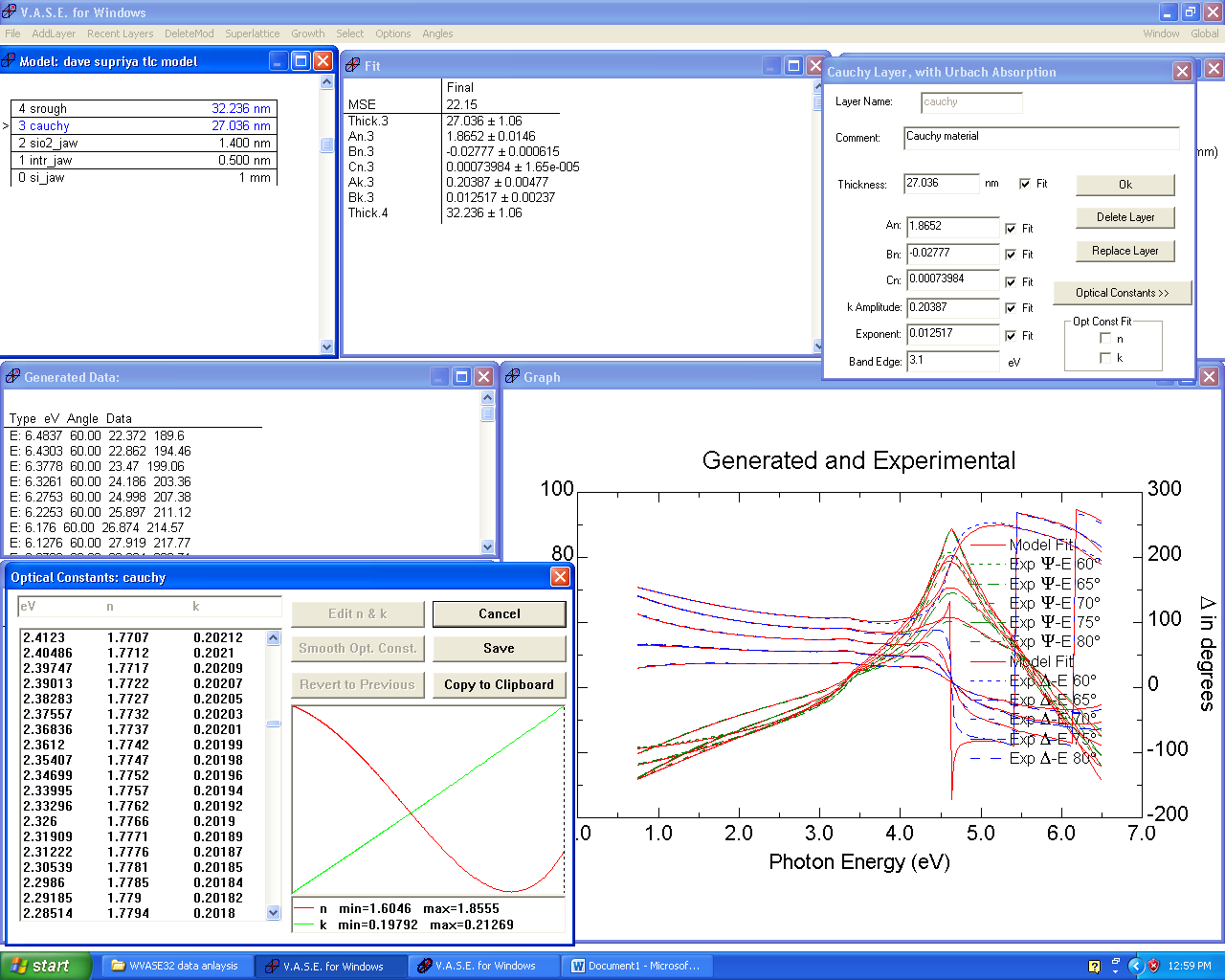


B. center;

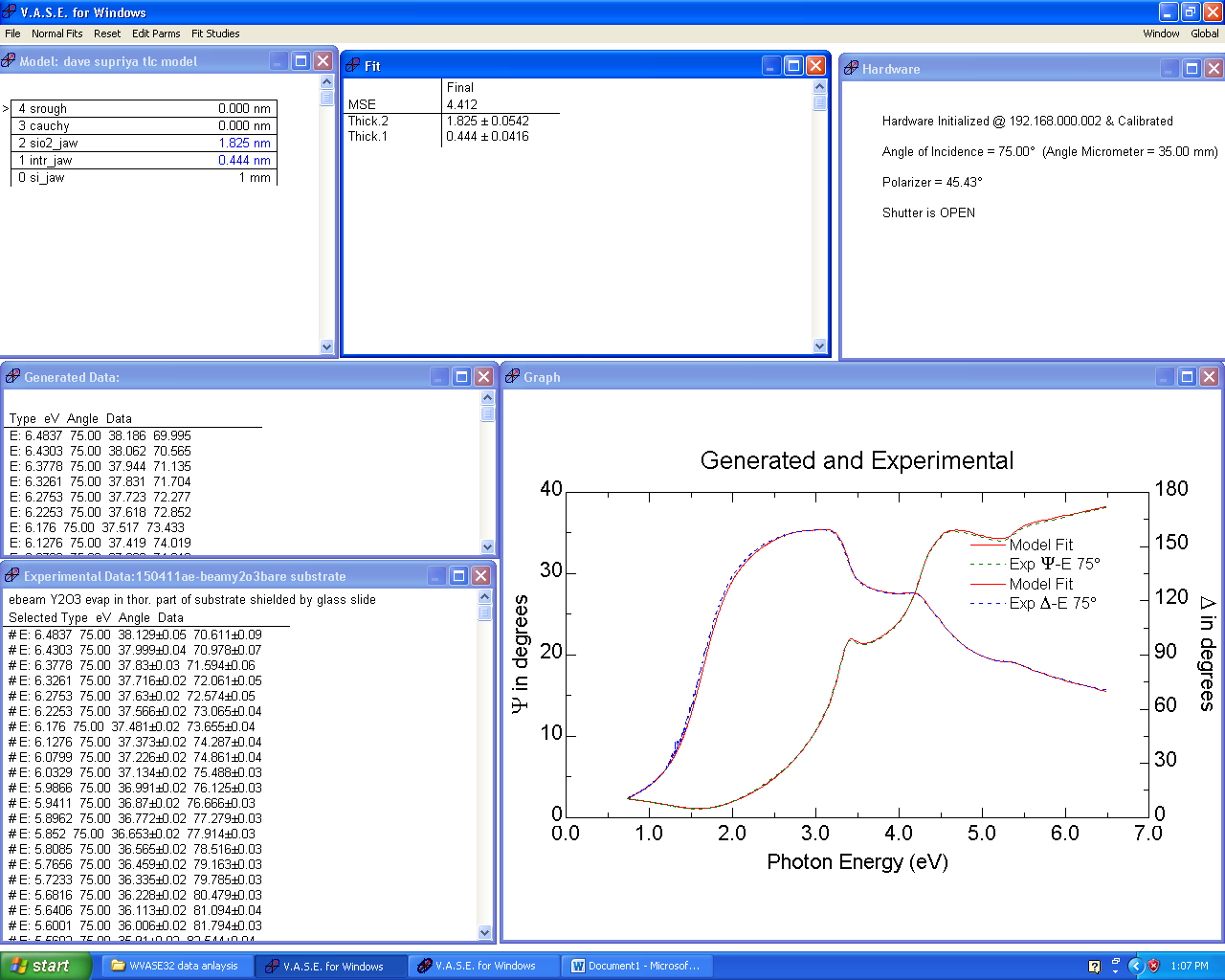


Vary parameters

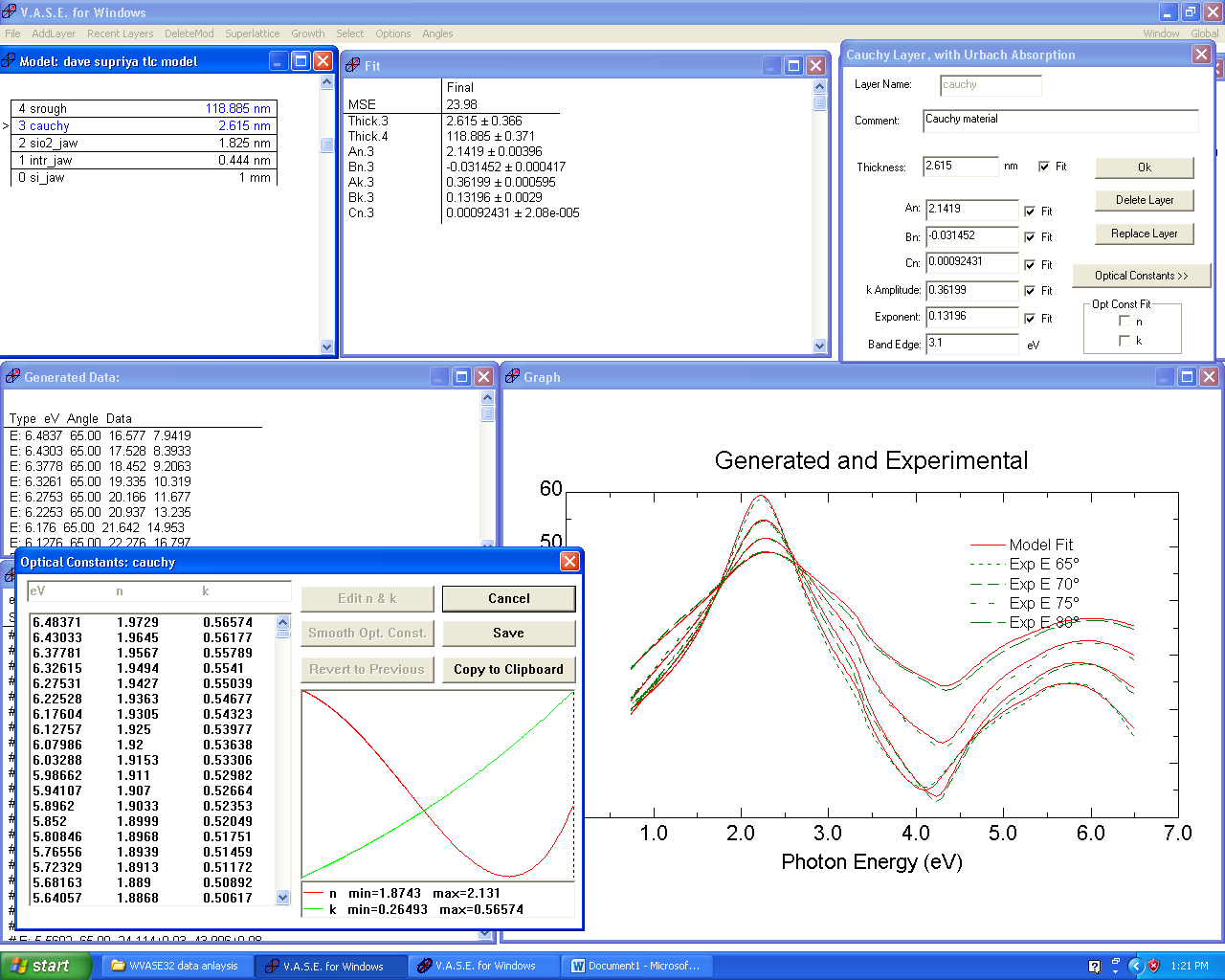


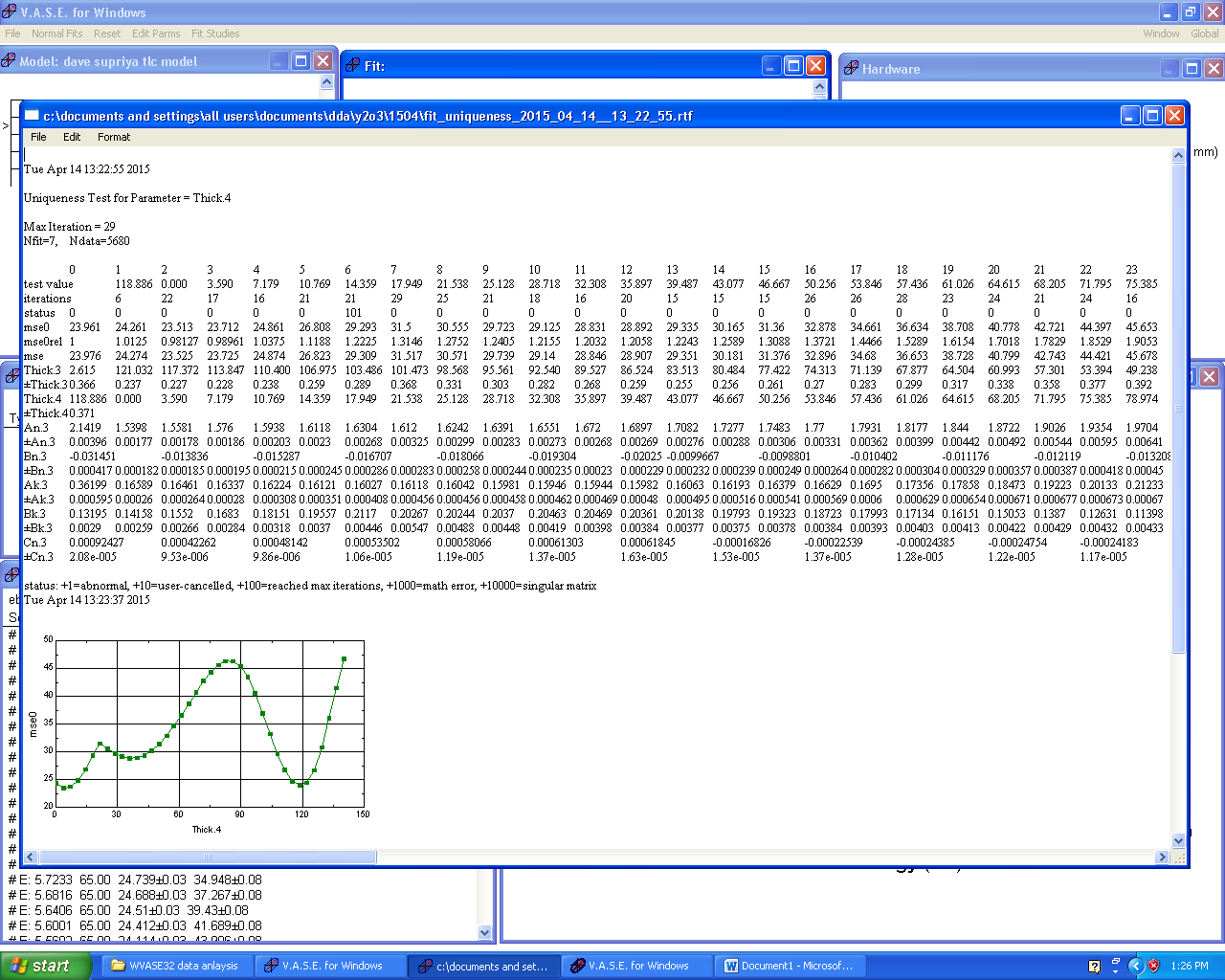


Bare wafer A.



Sample A.





Fit at low roughness.

